

# CBC powering

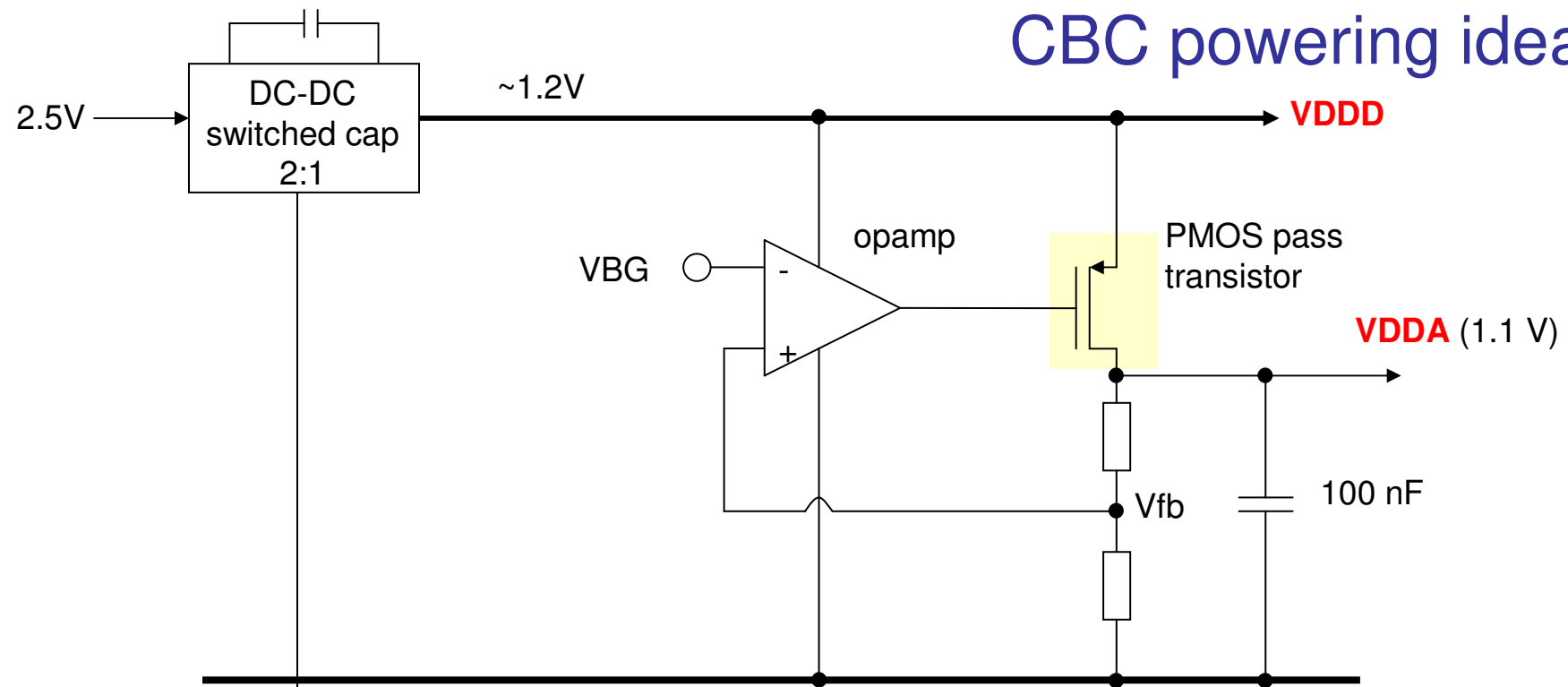
can CBC3 be powered from 1.2V +/- 5% ?

=> 1.14 - 1.26 V

upper limit for CBC

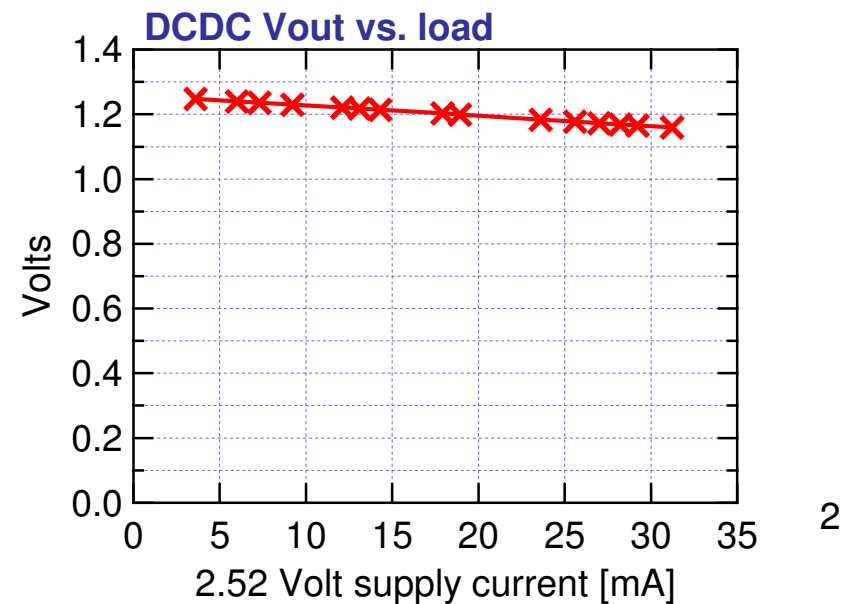
130 nm technology allows VDD up to 1.6 V

lower limit dictated by correct circuit functionality



switched cap. DC-DC  
 does not have to be used  
 may well work well in bump-bond layout

in reality needs >2.5V to guarantee  
 LDO input > 1.2V



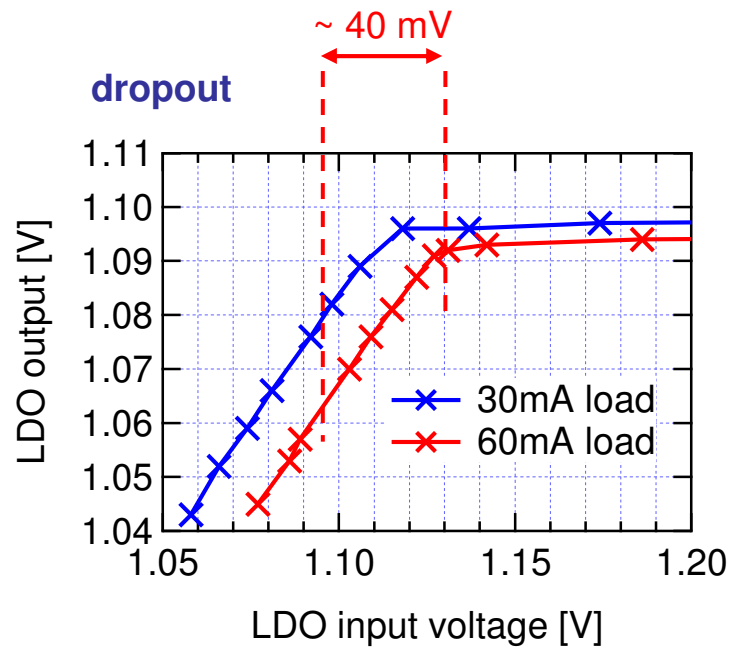
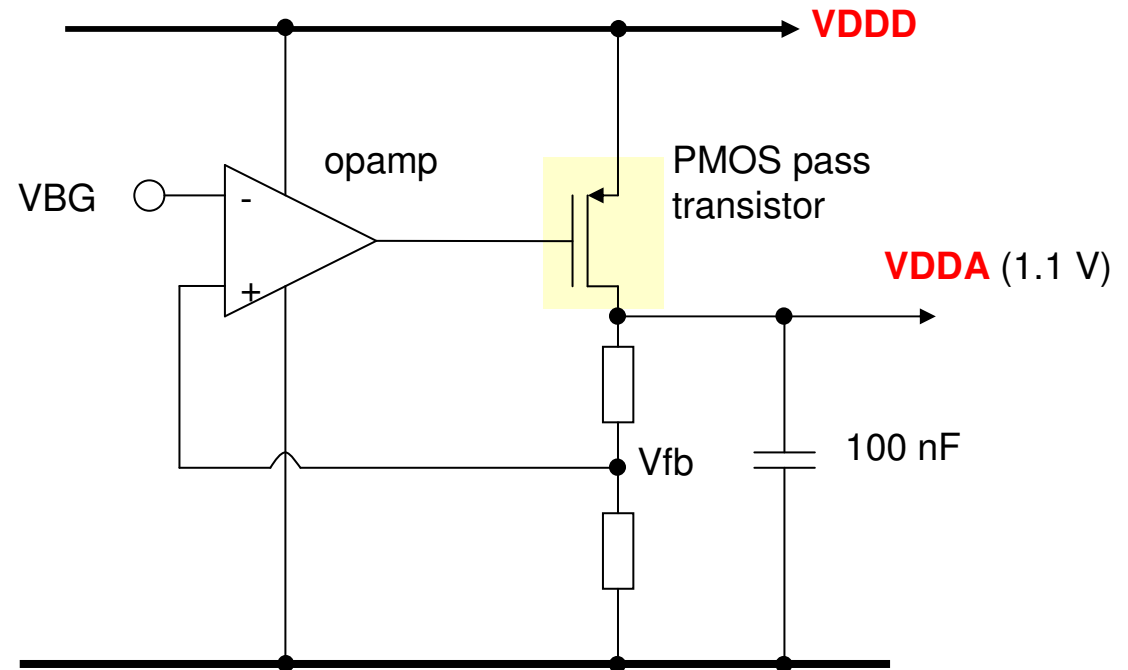
# ignoring switched cap DC-DC

how low can VDDD go?

have to accommodate dropout

have to allow for variations in VBG

have to supply minimum acceptable voltage level for VDDA



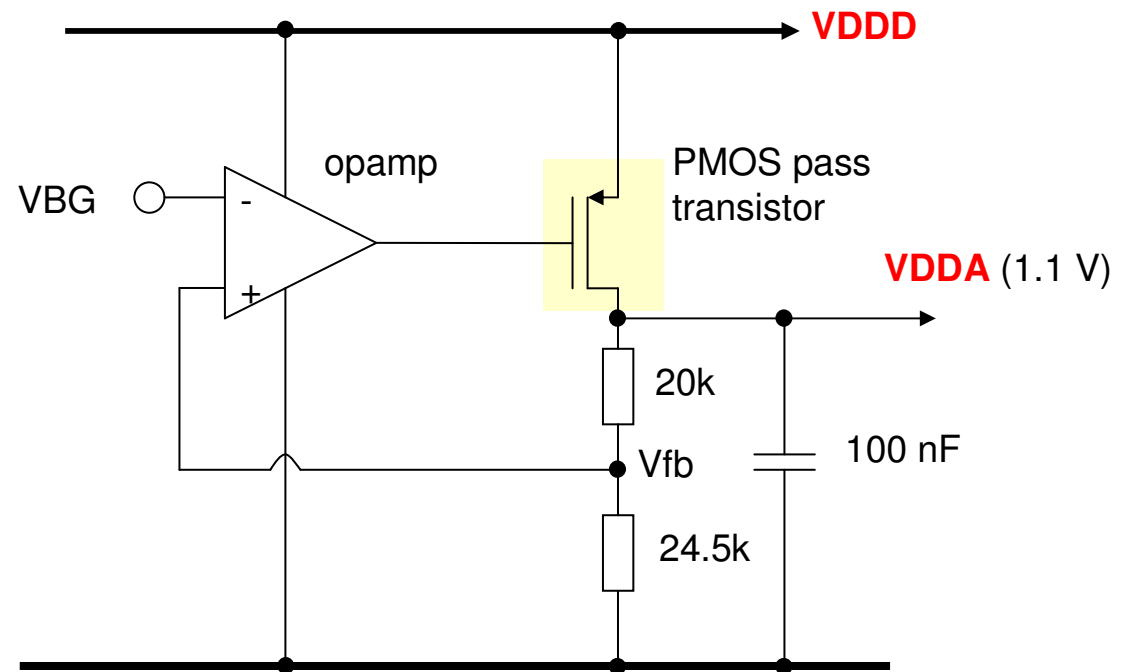
# VBG tolerance

VBG measurement data provided

619mV +/- 7.4 mV rms

taking +/- 3 sigma as limits

619 +/- 22 mV (597 - 641)mV



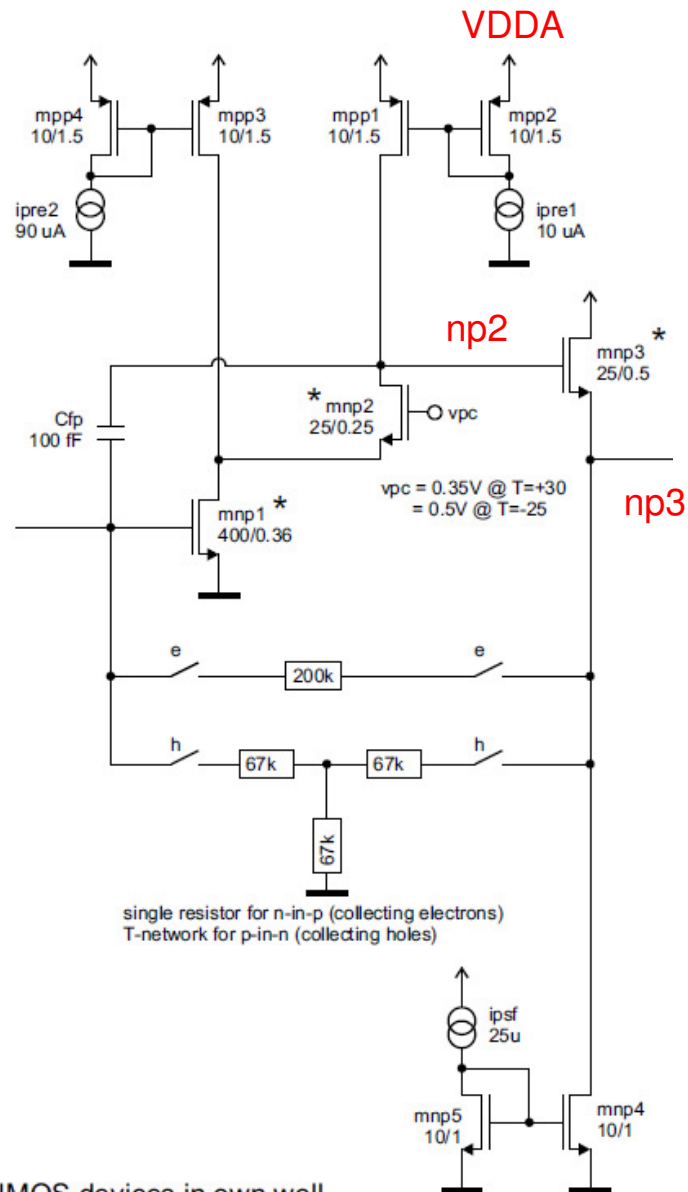
$$VDDA = 1.82 \times VBG$$

$$= 1.09 - 1.17 \text{ (slightly oversized to allow for series resistance at LDO output)}$$

so VDDD of 1.2V minimum is just about ok (actually a bit marginal)

anything less and LDO will not work correctly

# but could analogue stages work at lower VDDA?



design simulation conditions:

+40 -> -40 temperature range

$|I_{LEAK}| = 0 \rightarrow 1 \mu A$

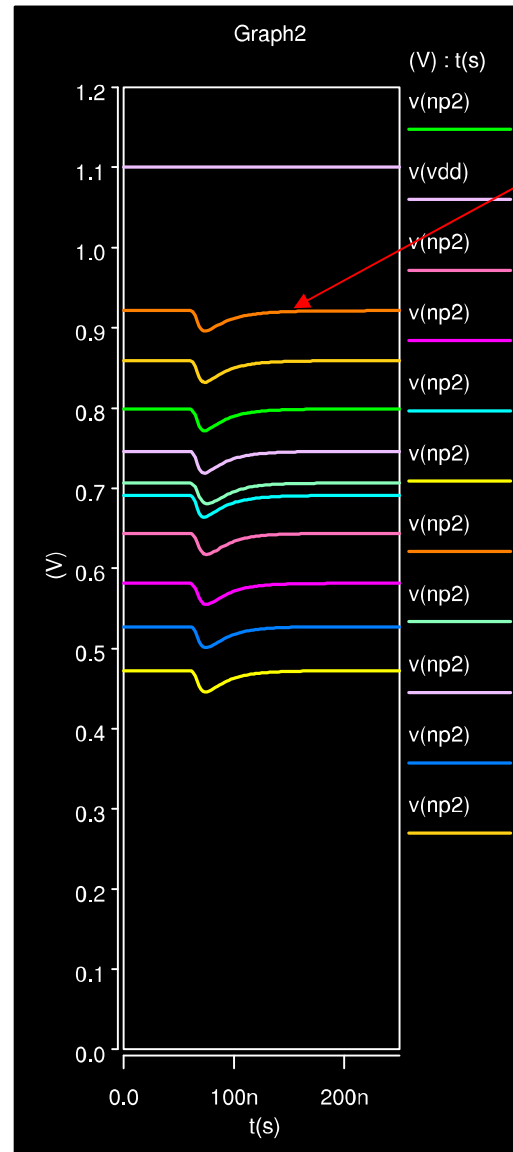
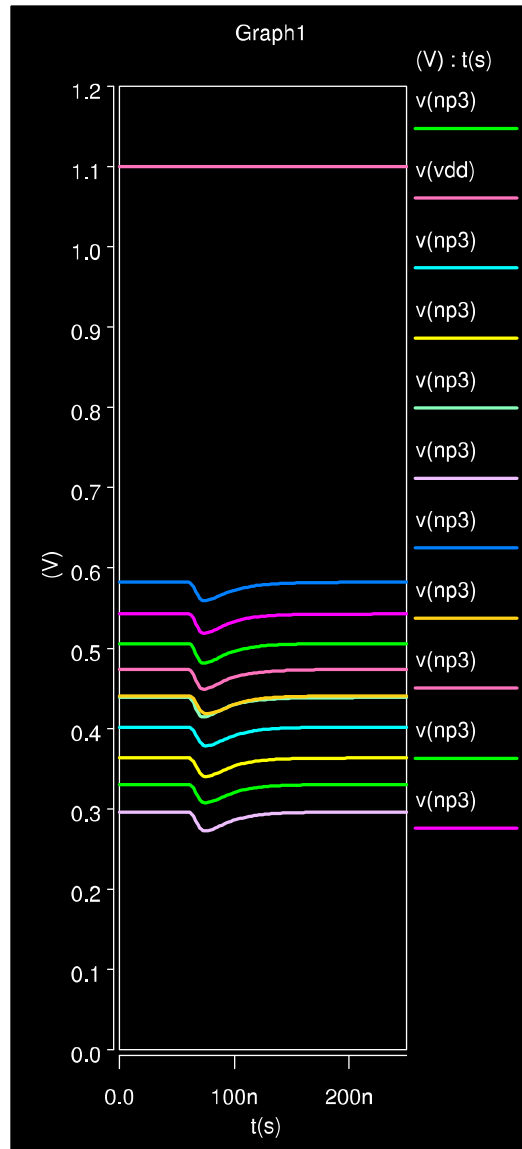
all process corners

TT, FF, SS, FS, SF

goal to achieve a very robust design

\*NMOS devices in own well

# VDDA = 1.1V



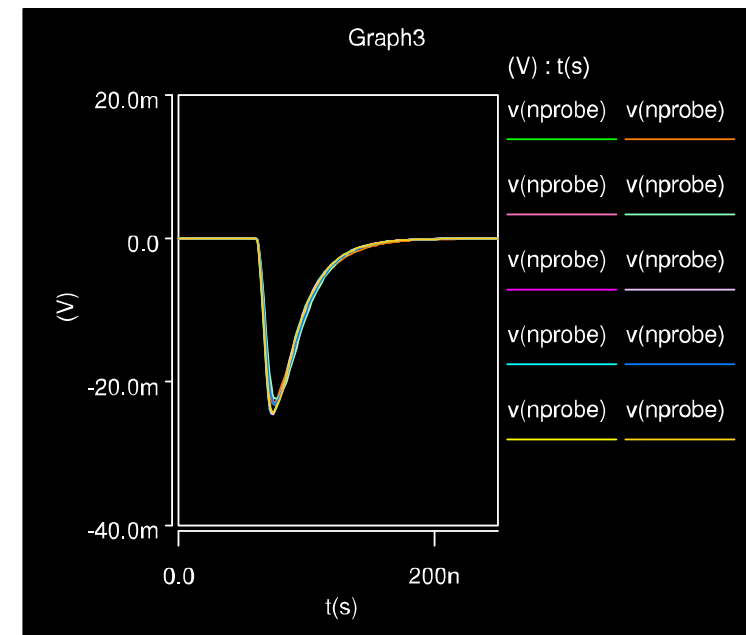
worst case is holes mode

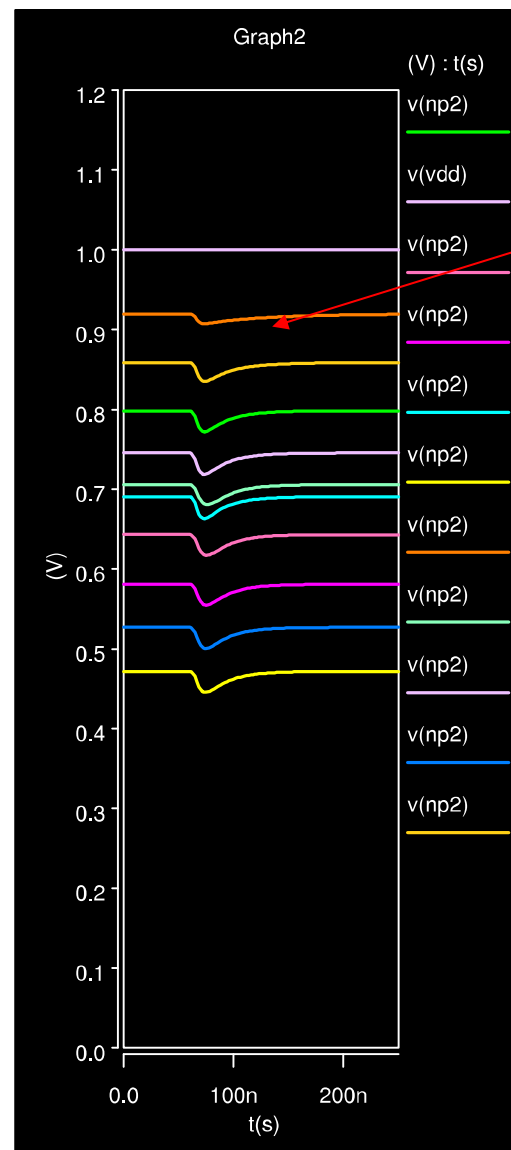
$I_{LEAK} = 0$

$T = -40$

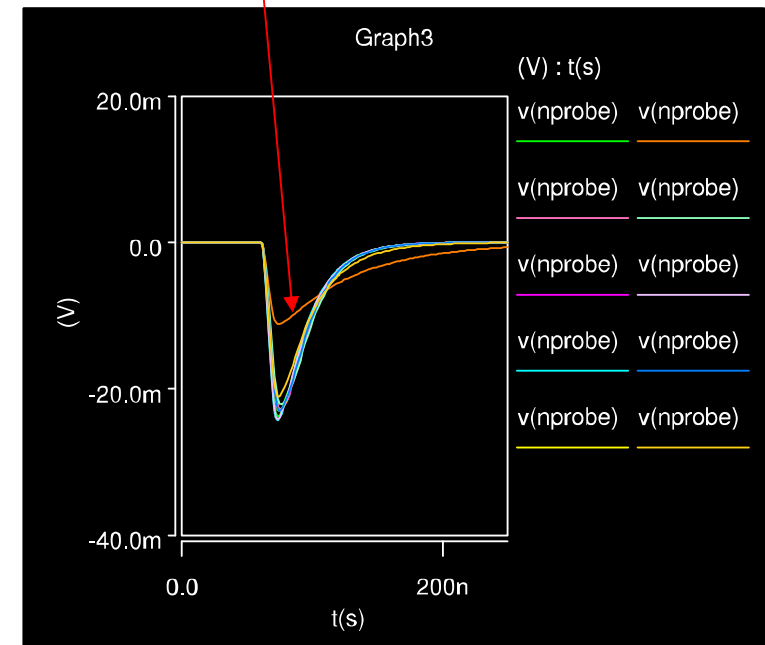
SS corner

but OK here for VDDA = 1.1V

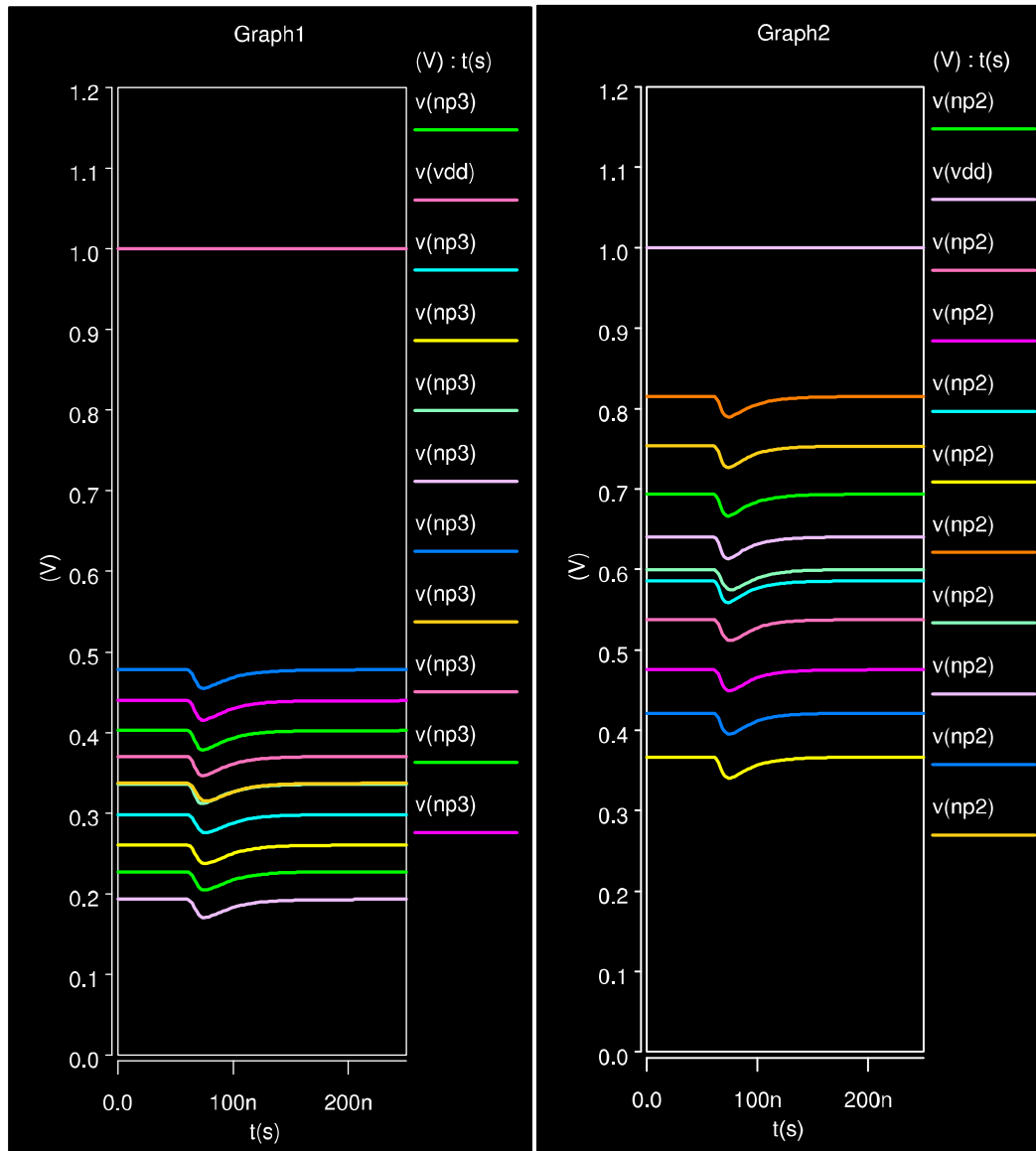




SS corner

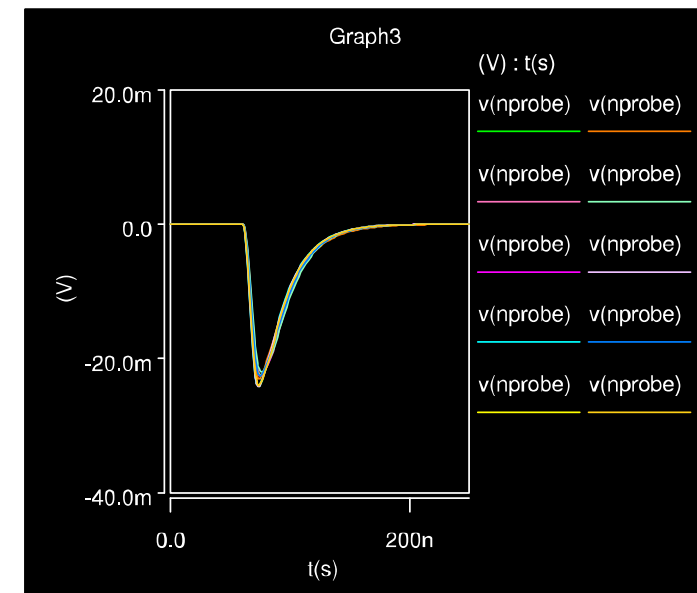


$$V_{DDA} = 1.0V$$



goes away with leakage  
as DC level decreases

$$I_{LEAK} = 0.5 \mu A$$





# what to do?

- tweak analogue design to run at 1.0V and adjust LDO?
  - can try again, but no guarantee of success
  - (spent some time looking at this in original design phase)

- would like to avoid major modifications to front end if possible

- adjust LDO for 1.0 V and hope we don't see the problem?
  - probably unlikely to see this process corner?

- impose additional constraints on other parts of system?
  - e.g. insist on sensor AC coupling?

## some final thoughts

are we doing the right thing trying to force two technologies to the same supply?

forces 65nm chips to high end of operational range

1.2 +/- 5% rather “fine tuned”

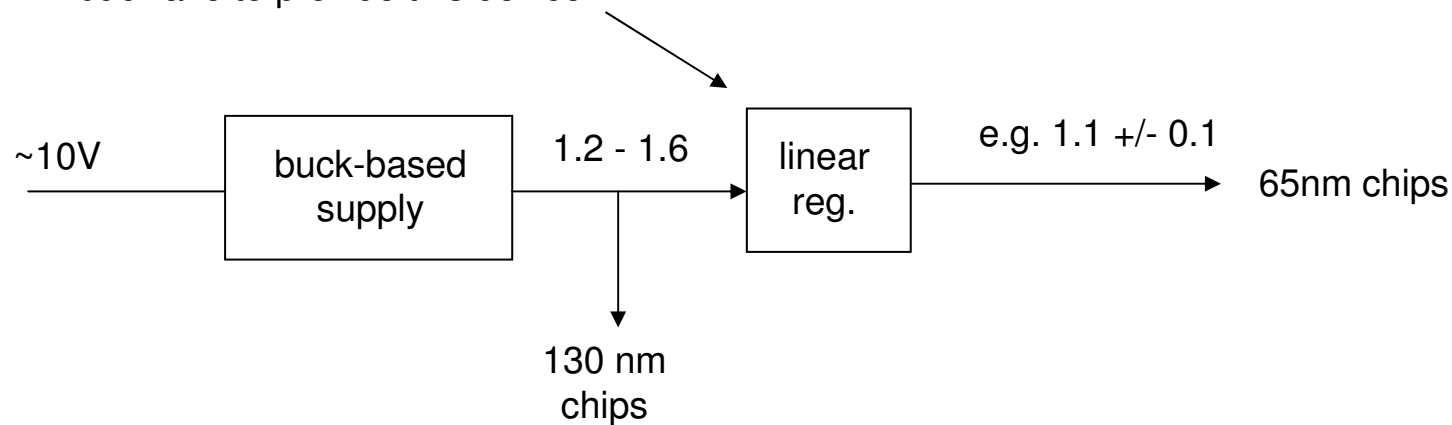
maybe over-constrains power supply design?

could derive 65nm rail from 130nm rail?

removes restriction on 130nm supply & increases tolerances

offers some protection to 65nm chips (& can also increase tolerance)

**but** have to provide this device



what about ripple on 1.2 +/- 5% ?

i.e. will the lower limit be less than 1.14 (1.14 +/- some level of ripple) ?